# **Power MOSFET**

# 30 V, 58.5 A, Single N-Channel, SO-8 FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Thermally Enhanced SO-8 Package
- These are Pb-Free Device

#### **Applications**

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters
- High Side Switching

# MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Voltage		$V_{GS}$	±20	V	
Continuous Drain		T <sub>A</sub> = 25°C	Ι <sub>D</sub>	13.8	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 85°C		10	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.14	W
Continuous Drain	]	T <sub>A</sub> = 25°C	Ι <sub>D</sub>	22.4	Α
Current R <sub>θJA</sub> ≤ 10 sec		T <sub>A</sub> = 85°C		16.1	
Power Dissipation $R_{\theta JA,} t \leq 10 \text{ sec}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	5.61	W
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	8.8	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 85°C		6.4	
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.87	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	58.5	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C		42.3	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	38.5	W
Pulsed Drain Current	t <sub>p</sub> =10μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	117	Α
Current limited by pa	Current limited by package T <sub>A</sub> = 25°C			100	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Source Current (Body Diode)		I <sub>S</sub>	38.5	Α	
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 50 V, $V_{GS}$ = 10 V, $I_L$ = 24 $A_{pk}$ , L = 0.3 mH, $R_G$ = 25 $\Omega$ )		EAS	86	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T <sub>L</sub>	260	°C

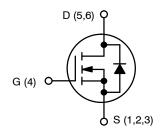
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



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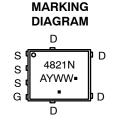
#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
30 V	6.95 m $\Omega$ @ 10 V	50 F A	
	10.8 mΩ @ 4.5 V	58.5 A	



**N-CHANNEL MOSFET** 





Α = Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4821NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4821NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.25	
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	58.3	°C ///
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	144.1	°C/W
Junction-to-Ambient - t ≤ 10 sec	$R_{ heta JA}$	22.3	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

# FLECTRICAL CHARACTERISTICS /T.

Parameter	Symbol	mbol Test Condition			Тур	Max	Unit
OFF CHARACTERISTICS							•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				25		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25 °C			1	
			T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.45	1.8	2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>						mV/°C
Drain-to-Source On Resistance	$R_{DS(on)}$ $V_{GS} = 10 \text{ V to}$ $-11.5 \text{ V}$ $-11.5 \text{ V}$ $-11.5 \text{ V}$		I <sub>D</sub> = 30 A		5.3	6.95	
		I <sub>D</sub> = 15 A		5.2			
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		8.6	10.8	mΩ
			I <sub>D</sub> = 15 A		8.4		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 30 A			54		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				1400		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V			282		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				136		
Total Gate Charge	Q <sub>G(TOT)</sub>				10.7	16	
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			1.4		nC
Gate-to-Source Charge	$Q_{GS}$				4.1		
Gate-to-Drain Charge	$Q_{GD}$				3.8		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 30 \text{ A}$			25		nC
SWITCHING CHARACTERISTICS (Note 4)							
					13.3		
Turn-On Delay Time	t <sub>d(ON)</sub>				10.0		
Turn-On Delay Time Rise Time	t <sub>d(ON)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 1	5 V, I <sub>D</sub> = 15 A.		38		ns

3. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.

Fall Time

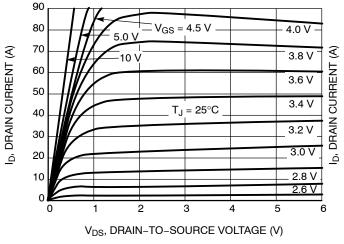
4. Switching characteristics are independent of operating junction temperatures.

3.8

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)			•	•		
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			8.2		- ns
Rise Time	t <sub>r</sub>				20		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				23		
Fall Time	t <sub>f</sub>				3.1		
DRAIN-SOURCE DIODE CHARACTE	ERISTICS						
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 30 A	T <sub>J</sub> = 25°C		0.85	1.0	V
			T <sub>J</sub> = 125°C		0.74		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dl_S/dt = 100 \text{ A/}\mu\text{s,}$ $l_S = 30 \text{ A}$			11		ns
Charge Time	t <sub>a</sub>				7.5		
Discharge Time	t <sub>b</sub>				3.5		
Reverse Recovery Charge	Q <sub>RR</sub>				2.0		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			1.3		nΗ
Drain Inductance	L <sub>D</sub>				0.005		1
Gate Inductance	L <sub>G</sub>				1.84		
Gate Resistance	$R_{G}$			0.5	1.1	2.0	Ω

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.



V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

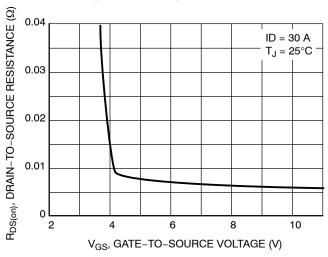


Figure 2. Transfer Characteristics

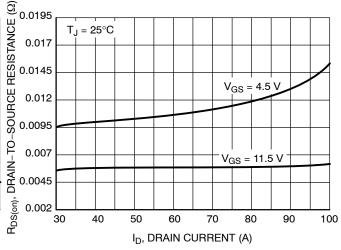
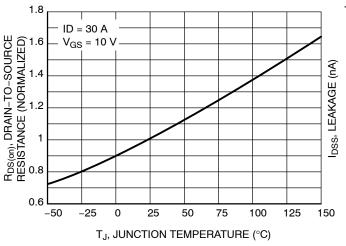


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



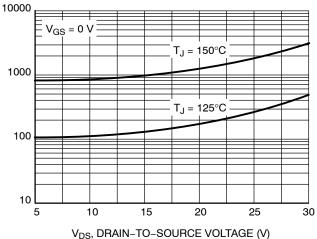


Figure 5. On-Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

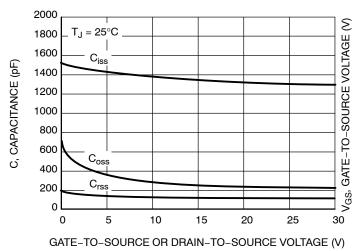


Figure 7. Capacitance Variation

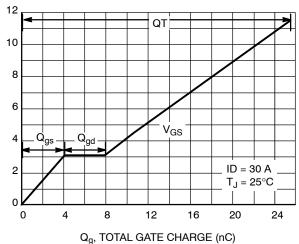


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

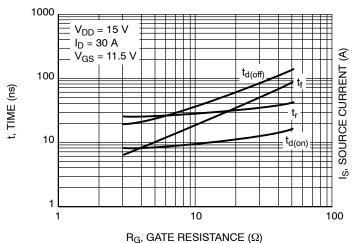


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

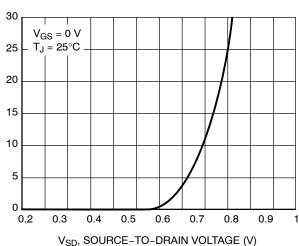


Figure 10. Diode Forward Voltage vs. Current

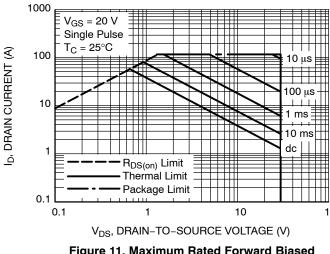


Figure 11. Maximum Rated Forward Biased Safe Operating Area

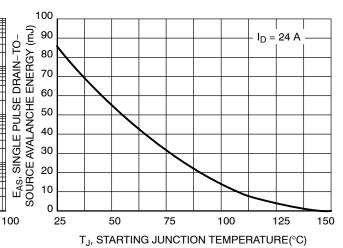
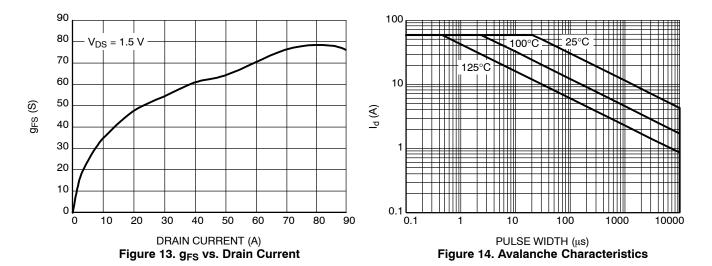
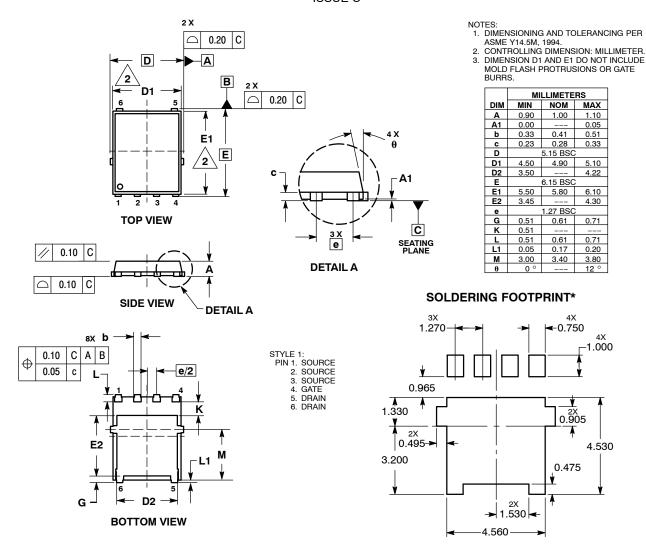


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature



#### PACKAGE DIMENSIONS

# **DFN6 5x6, 1.27P (SO8 FL)**CASE 488AA-01 ISSUF C



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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